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- Analog Portion of ADC and DAC for Audio-Band Signal-Processing Applications
- 5-V Supply Voltage
- Oversampling Second-Order Sigma-Delta Modulator
- 1.024-MHz Master Clock Frequency
- On-Chip Continuous-Time Antialiasing and Smoothing Filters
- High-Performance Fully Differential and Symmetrical Analog Data Paths
- Internal Reference Voltage and Common-Mode Bias Voltage Generation
- Very Low Power Consumption Mode



NC - No internal connection

description

The MSP58C20 is the analog portion of an audio-band sigma-delta analog-to-digital and digital-to-analog converter and is a companion part to the MSP58C80. The MSP58C20 is designed to operate only with the MSP58C80, which contains the digital portion of the audio-band converter. The circuit consists of three main blocks: the analog-to-digital converter (ADC), the digital-to-analog converter (DAC), and internal reference and bias voltages.

The analog-to-digital conversion chain consists of a continuous-time antialiasing stage, an analog oversampled modulator, and the modulator bias voltage. The antialiasing stage is a second-order low-pass filter with a cutoff frequency of typically 190 kHz. The modulator is a sigma-delta feedback loop, which oversamples the signal at 1.024 MHz and provides second-order noise shaping. It performs the conversion of the differential analog input signal to a pulse-density-modulated single-bit digital output (ADOUT). When a maximum positive differential input voltage (i.e., a maximum positive voltage difference of AIP – AIM) is applied at the AIP and AIM inputs, the resulting code at the ADOUT output is all ones.

The digital-to-analog conversion chain consists of a fast DAC, an analog low-pass filter, and the filter's bias voltage. The two input bits (DIGS and DIGL), sampled at 0.512 MHz from a digital modulator on the MSP58C80, are the inputs of the DAC conversion chain. Based on the values for DIGS (the sign bit) and DIGL (the level bit), the following table shows the DAC voltage steps that are produced.

DIGS	DIGL	DAC VOLTAGE STEPS
L	L	$-1 \times V_{ref}$
L	Н	$-2 \times V_{ref}$
Н	L	+1 \times V _{ref}
Н	Н	+2 \times V _{ref}

When DIGS = L, the AOM analog output has a more positive voltage than AOP. When DIGL = H, the absolute value of the voltage difference between AOP and AOM is greater than when DIGL = L. A band-gap voltage source is used to produce the DAC and ADC reference voltages. These two references are different to avoid crosstalk between the two converters.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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functional block diagram





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Terminal Functions

TERMI	NAL			
NAME	NO.	A/D	1/0	DESCRIPTION
ADCLK	14	D	I	ADCLK is a 1.024-MHz clock input.
ADOUT	8	D	0	ADOUT is the 1-bit output of the ADC modulator and is sampled at 1.024 MHz.
AIM	5	A	Ι	AIM is a negative differential input for the ADC. AIP and AIM together form a balanced differential input. The biasing of this terminal is fixed through resistors by the internal common-mode voltage source. This terminal can be ac coupled or dc coupled. If the terminal is dc coupled, external common-mode bias should satisfy recommended operating conditions.
AIP	4	A	I	AIP is a positive differential input for the ADC. AIP and AIM together form a balanced differential input. The biasing of this terminal is fixed through resistors by the internal common-mode voltage source. This terminal can be ac coupled or dc coupled. If the terminal is dc coupled, external common-mode bias should satisfy recommended operating conditions.
AOM	17	A	0	AOM is a negative differential DAC output. AOP and AOM together form a balanced differential output. The common-mode voltage at this terminal is fixed by the internal common-mode circuitry.
AOP	18	A	0	AOP is a positive differential DAC output. AOP and AOM together form a balanced differential output. The common-mode voltage at this terminal is fixed by the internal common-mode circuitry.
DIGL	15	D	I	DIGL is the input level bit of the DAC and is sampled at 0.512 MHz.
DIGS	16	D	I	DIGS is the input sign bit of the DAC and is sampled at 0.512 MHz.
PWAD	6	D		When PWAD is high, it puts the ADC part of the circuit into a power-down mode. When both PWAD and PWDA are high, the MSP58C20 is in a stable low-power-consumption state.
PWDA	7	D		When PWDA is high, it puts the DAC part of the circuit in a power-down mode. When both PWAD and PWDA are high, the MSP58C20 is in a stable low-power-consumption state.
VSUB	1	n/a	n/a	$V_{\mbox{SUB}}$ and $V_{\mbox{SS}}$ must be connected together to minimize substrate currents during power up, power down, and normal operation.
V _{DD}	13	n/a	n/a	V _{DD} is the 5-V power supply.
VSS	3	n/a	n/a	$V_{\mbox{SS}}$ is ground. The internal band-gap voltage and the common-mode bias voltages are referenced to $V_{\mbox{SS}}.$

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{DD} (see Note 1)	\ldots -0.3 V to 6 V
Input voltage range, V _I (any digital or analog input, see Note 1)	V to V _{DD} + 0.3 V
V _{SUB} , V _{SS} voltage range, relative to each other	-30 mV to 30 mV
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stg}	. $-65^{\circ}C$ to $150^{\circ}C$

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to VSS unless otherwise noted.



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recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{DD} (see Note 1)	4.75	5	5.25	V
High-level input voltage, digital inputs, VIH (see Note 1)	2			V
Low-level input voltage, digital inputs, VIL (see Note 1)			0.8	V
Maximum differential input voltage between AIP and AIM (ac or dc peak-to-peak voltage), $V_{\mbox{ID}}$	-3		3	V
Common-mode input voltage at AIP and AIM, $V_{\mbox{\rm IC}}$ (see Note 1)	0.45× V _{DD}	0.5 × V _{DD}	$0.55 \times V_{DD}$	V
Input clock frequency, ADCLK		1.024		MHz
Resistive load between AOP and AOM	15			kΩ
Capacitive load at AOP and AOM (at each output versus VSS)			50	pF
Operating free-air temperature, T _A	0		70	°C

NOTE 1: All voltage values are with respect to $\mathsf{V}_{\ensuremath{\mathsf{SS}}}$ unless otherwise noted.



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, ADCLK input frequency = 1.024 MHz, PWDA = L and PWAD = L (power-up mode) (unless otherwise noted)

supply current characteristics

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{DD}	Supply current	$\begin{array}{ll} PWAD=H, & PWDA=H, \\ Digital inputs=V_{DD} \text{ or } V_{SS}, \\ Digital output=no load \end{array}$			50	μΑ
		PWAD = L, PWDA = L	6.5	9	16	mA

analog input characteristics

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Transmit dynamic range, maximum differential input voltage (between AIP and AIM)		dc or ac voltage	±2.22	±2.36	±2.5	V
VIO	Transmit differential input offset voltage		See Note 2	-150		150	mV
VIC	Internal common-mode voltage at AIP and AI	М		$0.4 \times V_{DD}$	0.5× V _{DD}	0.6 imes V _{DD}	V
-		AIP	Between AIP and internal common-mode voltage source (AIM = V _{DD} /2)	15	25	35	kQ
21	input impedance		Between AIM and internal common-mode voltage source (AIP = $V_{DD}/2$)	15	25	35	K22
		AIP	Measured at 5 MHz between AIP and V _{SS} (AIM = $V_{DD}/2$)			50	۶E
	AIM		Measured at 5 MHz between AIM and V_{SS} (AIP = $V_{DD}/2$)			50	ΡΓ

NOTE 2: Calculated by linear regression based on five dc measurements between -1 V and 1 V

digital output characteristics

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOH	Digital high-level output voltage versus $V_{\mbox{SS}}$	I _{OH} = 300 μA	2.4			V
VOL	Digital low-level output voltage versus V_{SS}	I _{OL} = 1 mA			0.4	V

analog output characteristics

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
VOD	Differential output voltage, dynamic range, AOP to AOM	Balanced loads,	dc measurement	±2.82	±3	±3.18	V
Voo	Differential output offset voltage	dc measurement		-150		150	mV
Voc	Common-mode output voltage at AOP and AOM			$0.4 \times V_{DD}$	$0.5 \times V_{DD}$	$0.6 \times V_{DD}$	V



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, ADCLK input frequency = 1.024 MHz, PWDA = L and PWAD = L (power-up mode) (unless otherwise noted) (continued)

ADC transmit characteristics[†]

	PARAMETER	TEST	CONDITIONS		MIN	TYP	MAX	UNIT
	Transmit absolute gain tolerance	V _{DD} = 5 V, Input = 1-kHz sine wave at -1	T _A = 25°C, I3 dBrl				±0.5	dB
		Input = 1-kHz sine wave,	Input level = -1 dBrl to -4	13 dBrl			±0.25	
	Transmit gain versus	Gain reference level = gain	Input level = -43 dBrl to -	-53 dBrl			±0.5	dB
	inputievei	–13 dBrl, See Note 3	Input level = -53 dBrl to -	-58 dBrl			±1	
	Transmit gain versus supply voltage	V_{DD} = 4.75 V to 5.25 V,	Input = 1 kHz at – 13 dBrl	Input = 1 kHz at – 13 dBrl			±0.15	dB
	Transmit idle channel in-band noise	Psophometrically-weighted ou Transmit channel idle	utput noise,			-76		dBrlp
				f = 50 Hz		-80		
			f			-82		
	Transmit idle channel	$T_{\Lambda} = 25^{\circ}C_{\circ}$		f = 3.4 kHz		-82		
	single-frequency noise	FFT rectangular window band	lwidth = 125 Hz,	f = 4 kHz		-80		dBrl
spectrum (see Note 4) Transmit	Transmit channel idle,	nit channel idle, See Figure 5			-72			
				f = 12 kHz		-65		
			f = 20			-64		
	Transmit single- frequency distortion	Input = one frequency in 0.7-k Measured first two harmonics	Input = one frequency in 0.7-kHz to 1.1-kHz band at -4 dBrl, Measured first two harmonics				-50	dB
	Transmit intermodulation distortion (see Note 4)	Input = two frequencies in 0.3 Input levels = -7 dBrl and -2 . Measured second and third in	-kHz to 3.4-kHz band, 4 dBrl, termodulation products				-40	dBrl
		V _{DD} = 5.25 V, T _A = 25°C,	Input level = -70 dBrl		-13			
	noise-plus-distortion ratio	Input = 1-kHz sine wave, Measured psophometrically-	Input level = -20 dBrl		50			dB
	(see note 5)	weighted total noise plus distortion, See Figure 6	Input level = -1 dBrl		50			
	Transmit gain variations versus input frequency (see Notes 4 and 6)	f = 0.1 kHz to 4 kHz,	Input level = -13 dBrl				±0.6	dB
	Transmit power supply rejection	See Note 7			30			dB
	Lookogo ourront	Voltage applied to terminal is	between V _{SS} and V _{DD} ,	AIP	-10		10	
likg	Leakage current	PWDA = H (power-down mod	le)	AIM	-10		10	μΑ
	Receive-to-transmit crosstalk	Receive input = one frequenc Crosstalk measured at transm Transmit channel idle	y in 0.3-kHz to 3.4-kHz bar nit digital output,	ıd at −3 dBrl,			-70	dB

[†] This table contains specifications in which the power levels are expressed in dBrl; dBrl stands for dB above reference level. 0 dBrl is the ADC theoretical overload point. This overload point corresponds to a sine wave at the input of the modulator with peak amplitude equal to 2.25 V dBrlp is a psophometrically-weighted value being compared against a psophometrically-weighted reference.

NOTES: 3. Input satisfies CCITT G.714 15.3, Method 2.

- 4. This parameter is characterized but not tested.
- 5. Input satisfies CCITT G.714 14.3, Method 2.
- 6. Gain is relative to gain at 1 kHz.
- 7. The power-supply rejection measurement is made with a 50-mVrms, 0- to 20-kHz signal applied to V_{DD} and with the transmit channel idle.



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, ADCLK input frequency = 1.024 MHz, PWDA = L and PWAD = L (power-up mode) (unless otherwise noted) (continued)

DAC receive characteristics[†]

PARAMETER	TEST CON	NDITIONS	MIN	TYP	MAX	UNIT
Receive gain tolerance	V _{DD} = 5 V, Input = 1-kHz sine wave at –28 dBrl	T _A = 25°C,			±0.5	dB
	Input = 1-kHz sine wave,	Input level = -1 dBrl to -43 dBrl			±0.25	
Receive gain versus input level	Gain reference level = gain	Input level = -43 dBrl to -53 dBrl			±0.5	dB
	See Note 8	Input level = -53 dBrl to -58 dBrl			±1	
Receive gain versus supply voltage	V _{DD} = 4.75 V to 5.25 V, Digital input = 1-kHz sine wave at -2	28 dBrl			±0.15	dB
Receive idle channel in-band noise	Receive channel idle, Psophometrically-weighted output no	pise		-75		dBrlp
	$T_{A} = 25^{\circ}C$	f = 100 Hz		-82		
Receive idle channel	Receive channel idle,	f = 3 kHz		-82		dBri
spectrum (see Note 4)	Measurement bandwidth = 125 Hz, See Figure 6	f = 10 kHz		-64		abri
		f = 100 kHz		-64		
Receive single-frequency distortion	Input = one frequency in 0.7-kHz to Measured first two harmonics	1.1-kHz band at −6 dBrl,			-50	dB
Receive intermodulation distortion (see Note 4)	Input = two frequencies in 0.3-kHz to Input levels = -7 dBrl and -24 dBrl, Measured second and third intermod	o 3.4-kHz band, dulation products			-40	dBrl
Receive signal-to-total-noise-	$V_{DD} = 5.25 \text{ V}, T_A = 25^{\circ}\text{C},$	Input level = -70 dBrl	0			
plus-distortion ratio	Measured psophometrically-	Input level = -20 dBrl	50			dB
(see note 9)	distortion, See Figure 7	Input level = -1 dBrl	50			
		f = 156 Hz to 4 kHz	-0.6‡		0.6	
		f = 4.6875 kHz	-0.7		-0.4	
		f = 6.25 kHz	-1.75		-1.4	
Receive gain variations versus	$V_{DD} = 4.75 V$, $T_A = 25^{\circ}C$,	f = 7.8125 kHz	-3.35		-2.9) dB 3
(see Note 6)	See Figure 9	f = 9.375 kHz	-5.25		-4.8	
	-	f = 10.9375 kHz	-7.25		-6.8	
		f = 12.5 kHz	-9.2		-8.7	
		f = 15.625 kHz	-12.8		-12.2	
Receive power supply rejection	See Note 10		30			dB

⁺ This table contains specifications in which the power levels are expressed in dBrl; dBrl stands for dB above reference level. 0 dBrl is the DAC overload point. Overload levels of the digital modulator (see parameter measurement information) are 32767 and –32767 peak values. The 0-dBrl level is related to maximum differential output voltage, which is typically 2.25 V.

[‡] The algebraic convention, in which the less positive (more negative) limit is designated as minimum, is used in this data sheet for receive gain variations versus input sine-wave frequency.

NOTES: 4. This parameter is characterized but not tested.

6. Gain is relative to gain at 1 kHz.

- 8. Input satisfies CCITT G.714 15.4 Method 2.
- 9. Input satisfies CCITT G.714 14.4 Method 2.
- 10. The power supply rejection measurement is made with a 50-mVrms, 0-kHz to 20-kHz signal applied to V_{DD} and with the receive channel idle.



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature, ADCLK input frequency = 1.024 MHz, PWDA = L and PWAD = L (power-up mode) (unless otherwise noted) (continued)

DAC receive characteristics (continued)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
1	Lookogo ourropt	AOP	-10		10	
likg	Leakage current	AOM	-10		10	μΑ
	Output impedance, differential, between AOP and AOM (see Note 4)		30			kΩ
	Transmit-to-receive crosstalk	Transmit input = one frequency in 0.3-kHz to 3.4-kHz band at –3 dBrl, Receive channel idle, Crosstalk measured at receive analog output			-70	dB

NOTE 4. This parameter is characterized but not tested.

timing requirements over recommended ranges of supply voltage and operating free-air temperature

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{su1}	Transmit setup time at power up (PWAD transition from H to L)	ADCLK input frequency = 1.024 MHz, See Note 11		20		μs
t _{su2}	Receive setup time at power up (PWDA transition from H to L)	ADCLK input frequency = 1.024 MHz, See Note 12		20		μs
t _{su3}	Receive setup time, DIGS or DIGL setup before ADCLK \uparrow	See Figure 4	50			ns
t _h	Receive hold time, DIGS or DIGL hold after ADCLK \uparrow	See Figure 4	50			ns
t _C	Cycle time, ADCLK			1		μs
tw1	Pulse duration, ADCLK high		470			ns
tw2	Pulse duration, ADCLK low		470			ns
tf	Fall time, ADCLK				20	ns
tr	Rise time, ADCLK				20	ns

NOTES: 11. After the setup time, the transmit channel displays normal operating characteristics.

12. After the setup time, the receive channel displays normal operating characteristics.

switching characteristic over recommended ranges of supply voltage and operating free-air temperature

	PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
^t a	Transmit access time, ADOUT after ADCLK \uparrow (see Note 4)	See Figure 3			100	ns

NOTE 4. This parameter is characterized but not tested.



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PARAMETER MEASUREMENT INFORMATION

The receive characteristics in the electrical characteristics table are measured by activating the MSP58C20 receive path through a digital modulator. This modulator consists of two functional blocks (see Figure 1 and Figure 2) connected in series. The output of the decoder (see Figure 2) is shown in Table 1.



Figure 1. 16- to 13-Bit Modulator at 512-kHz Sampling Rate



Figure 2. Sigma-Delta-2 Modulator at 512-kHz Sampling Rate

DECODER INPUT				DECODER OUTPUT				
Vx (11)	Vx (10)	Vx (9)	Vx (8)	Dx (2)	Dx (1)	Dx (0)	DIGS	DIGL
0	1	Х	Х	Н	Н	L	L	Н
0	0	1	Х	Н	Н	L	L	н
0	0	0	1	Н	Н	L	L	Н
0	0	0	0	Н	Н	Н	L	L
1	1	1	1	L	L	Н	Н	L
1	1	1	0	L	Н	L	Н	Н
1	1	0	Х	L	Н	L	Н	Н
1	0	Х	Х	L	Н	L	Н	Н

Table 1. Dx Decoder



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PARAMETER MEASUREMENT INFORMATION



Figure 3. Transmit Access Timing Waveforms



Figure 4. Receive Setup and Hold Time Waveforms



(100, -64)

80

100

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TYPICAL CHARACTERISTICS



qualification standards, which every MSP58C20 must pass. The curve shows empirical data from a representative lot.

Figure 7



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TRANSMIT SIGNAL-TO-TOTAL-NOISE-**PLUS-DISTORTION RATIO** vs ANALOG INPUT SIGNAL MAGNITUDE Transmit Signal-to-Total-Noise-Plus-Distortion Ratio – dB 70 G V_{DD} = 5.25 V н T_A = 25°C 60 See Note A 50 (-1,50) Е 40 (-20,50) D 30 С в 20 10 **A**(0 -10 (-70, -13) -20 -80 -70 -60 -50 -40 -30 -20 -10 0 Analog Input Signal Magnitude – dBrl

NOTE A. The three points on the dashed line are minimum qualification standards, which every MSP58C20 must pass. The curve shows empirical data from a representative lot.

SET OF POINTS	LOCATION
А	(-70,8)
В	(–58, 20)
С	(–53, 24)
D	(–43, 32)
E	(–35, 40)
F	(–28, 48)
G	(–13, 65)
Н	(5, 69)
I	(–1, 69)

Figure 8

TYPICAL CHARACTERISTICS



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MAXIMUM AND MINIMUM CHARACTERISTICS



SET OF POINTS	MIN	МАХ
А	(0.156, -0.6)	(0.156, 0.6)
В	(4, -0.6)	(4, 0.6)
С	(4.6875, -0.7)	(4.6875, -0.4)
D	(6.25, -1.75)	(6.25, -1.4)
E	(7.8125, -3.35)	(7.8125, -2.9)
F	(9.375, -5.25)	(9.375, -4.8)
G	(10.9375, -7.25)	(10.9375, -6.8)
Н	(12.5, -9.2)	(12.5, -8.7)
	(15.625, -12.8)	(15.625, -12.2)

Figure 9



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MECHANICAL DATA

DW (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE





NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013



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